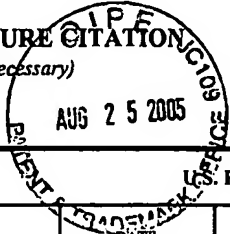


<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				Docket Number (Optional) <b>L0008/US</b>		Application Number <b>10/518,985</b>	
				Applicant(s) <b>Xavier Muyldermans, et al.</b>			
				Filing Date <b>December 21, 2004</b>		Group Art Unit <b>1752</b>	



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CPG		4,940,650	7-10-1990	Kurtz et al.			
CPG		5,112,725	5-12-1992	Kurtz et al.			
CPG		5,472,824	12-5-1995	Schober et al.			

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
CPG		0 691 991 B1	10-1-1997	EP				

OTHER DOCUMENTS			(Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER <i>Chris P. Johnson</i>	DATE CONSIDERED <i>3/7/06</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	Docket Number (Optional) <b>L0008/US</b>	Application Number <b>10/518,985</b>
	Applicant(s) <b>Xavier Muyldermans, et al.</b>	
	Filing Date <b>December 21, 2004</b>	Group Art Unit <b>Unknown</b>

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
C/g		4,126,466	11-21-1978	Roos			
C/g		4,266,005	5-5-1981	Nakamura et al.			
C/g		4,320,188	3-16-1982	Heinz et al.			
C/g		4,430,417	2-7-1984	Heinz et al.			
C/g		4,460,675	7-17-1984	Gruetzmacher et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
C/g		2002/0001775 A1	1-3-2002	Knoll			
C/g		2003/0232928 A1	12-18-2003	Atwood et al.			

**FOREIGN PATENT DOCUMENTS**

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	0 084 851 A2	8-3-1983	EP				
	0 525 206 A1	2-3-1993	EP				
	1 426 411 A1	6-9-2004	EP				
	1 431 349 A1	6-23-2004	EP				
	02/057386 A2	7-25-2002	WO				

**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*


EXAMINER <i>Cecilia P. Johnson</i>	DATE CONSIDERED <i>3/7/04</i>
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<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	Docket Number (Optional) <b>L0008/US</b>	Application Number <b>10/518,985</b>
	Applicant(s) <b>Xavier Muyldermans, et al.</b>	
	Filing Date <b>December 21, 2004</b>	Group Art Unit <b>Unknown</b>

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>CP</i>		5,213,948	5-25-1993	Abele			
<i>CP</i>		6,531,263	3-11-2003	Knoll			
<i>CP</i>		6,833,411	12-21-2004	Fujiwara et al.			

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS									
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation		
							YES	NO	
CP		1 366 769	9-11-1974	GB					
CP		2004-131707	4-30-2004	JP					

OTHER DOCUMENTS			(Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER <i>Charles P. Johnson</i>	DATE CONSIDERED <i>3/7/04</i>
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